





Characterization of P-type Silicon Detectors Irradiated with Neutrons

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3rd Workshop on Advanced Silicon Radiation Detectors, Barcelona, Spain

14 April 2008

Outline

- I. Fabrication process
- II. P-type µstrip detectors irradiated with neutrons
- III. Setup (Laser & Radiactive Source)
- IV. I-V results
- V. Q-V results
- VI. Summary and Outlook

I. Fabrication Process

Detectors have been fabricated in the Clean Room facility of CNM-IMB

Rd50 Mask

- Designed by the RD50 Collaboration
- Double side processing
- One metal layer

Structures

- 26 microstrips detectors
 - Polysilicon biasing resistors
 - Capacitive coupling
 - P-spray insulation
 - No p-stops
- 20 pad detectors
- 12 pixel detectors
- 8 test structure sets





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II. P-type µstrip detectors irradiated with neutrons

- Area: 1x1 cm²
- 130 strips, width: 32 μm
- Pitch: 80 μm
- Thickness: 300 μm
- Multiple guard ring
- Surface isolation: p-spray

DOFZ, MCz substrates to evaluate

I MeV equivalent neutron irradiation at TRIGA nuclear reactor in Ljubljana, Slovenia.

No annealing

Wire bonding









Laser light is generated by exciting a laser source with an external pulsed signal

(2 V and 1 MHz rate)

Laser properties:

- □ λ =1060 nm (Near Infrared)
- Laser energy of photons=1.170 eV

III. Radiactive Source Setup



 β Measurements are used to calibrate the laser measurements



IV. Current vs Voltage: DOFZ



For the sensor irradiated with 1×10^{14} n/cm² we observed an extremely early break

IV. Current vs Voltage: MCz



V. Charge vs Voltage: DOFZ * T = -40°C



V. Charge vs Voltage: MCz



Neutron Irradiation:

Comparison DOFZ vs MCz substrates at the same fluences



Degradation after neutron irradiation: Q- Φ



Collected charge is unaffected by the silicon substrate type

VI. Summary and Outlook

P-type μstrip sensors have been fabricated in CNM-IMB and irradiated with neutrons at several fluences at the TRIGA Nuclear Reactor in Ljubljana.

Detectors on alternative substrates (MCz, DOFZ) have been evaluated.

Current and Collected charge vs Voltage measurements have been done.

□ Even after the highest neutron fluence (equivalent to 10 years of the sLHC operation) the detectors are still operational.

For instance, at 8.0 10^{15} n/cm² ~7300 e- are collected at 900V.

□ MCz charge collection at high bias voltages to be understood.

The neutron radiation hardness does not depend on the substrate technology.

Near future plans, ALIBAVA system will be used to performance the charge collection measurements and signal characterization.

More neutron and proton irradiated detectores will be characterized in the coming months.